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Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date (if appropriate)
	AA						
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FOREIGN PATENT DOCUMENTS								
Examiner Initial		Document Number	Date	Name	Class	Sub- Class	TRANSLATION	
							Yes	No
<i>mf</i>	AK	4-358031	12/1992	Japan			Yes	
<i>ay</i>	AL	57-135776	08/1982	Japan			Yes	
<i>mf</i>	AM	3-177384	08/1991	Japan			Yes	
	AN							
	AO							
	AP							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)									
AQ	Japanese Office Action with English Translation								
AR									
AS									
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